

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		ATTY DOCKET NO. <b>00862.022541.</b>		APPLICATION NO. <b>10/091,461</b>	
APPLICANT <b>MASATAKA ITO</b>				<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block;">             OIPE JC18              JUN 22 2005              PATENT &amp; TRADEMARK OFFICE           </div>	
FILING DATE <b>March 7, 2002</b>		GROUP <b>2812</b>			

  

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	

  

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
X							
SDI	0 926 707	06/30/1999	EP				
I	0 926 718	06/30/1999	EP				
X	0 817 248	01/07/1998	EP				

  

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
SDI	H. Aga, et al., "Study of HF Defects in Thin, Bonded Silicon-on-Insulator Dependent on Original Wafers", Jpn. J. Appl. Phys., Vol. 38, May 1999, pp. 2694-2698.
SDI	G. Sasaki, et al., "Microstructure Around Indentation of Chemical Vapor Deposition (CVD)-SiC Observed by Transmission Electron Microscopy", Yogyo-Kyokai-Shi Japan, Vol. 94, No. 8, 1986, pp. 779-783.

  

EXAMINER <i>Stanley Lee</i>	DATE CONSIDERED <i>12/11/05</i>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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